**Text to be inserted in IBIS at the beginning of 2 STATEMENT OF INTENT or 6 BUFFER MODELING:**

Keywords and subparameters in IBIS files describe device behaviors in terms of data sets, to be used in combination with model equations and assumptions defined within EDA tools.  These data sets are generally assumed to have been collected using measurement or simulation under static conditions using a test fixture, under dynamic switching conditions or derived from data sheet information.

Unless stated otherwise, all device under test (DUT) voltages declared by keywords and subparameters are values with respect to a single reference node (often a DUT reference node such as 0.0 V value or ground used to extract the IBIS file model data).  Some keywords and subparameters may also describe how the data is expected to be used or measured.  Unless stated otherwise, all model data collections assume that the package values are not included.

During simulation (referred to as device in action or DIA), external voltages and loads may be applied to model terminals that are different than those used for DUT extraction.  Some EDA tools may choose to transform the simulation results back to DUT voltage levels for testing against certain specification information. In other words, IBIS buffer data generally describes a “device under test” (DUT), while the actual modeling of the collected data is performed by the EDA tool.